



IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Kenya KOBAYASHI

Conf. 3586

Application No. 10/607,064

Group 2812

Filed June 27, 2003

METHOD OF FORMING A TRENCH ISOLATION

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

April 29, 2004

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.

A concise explanation of the relevance of these items is that these references were cited by the Japanese Patent Office in the corresponding Japanese Application Serial No. 2000-286328, filed September 21, 2000. A copy of the Japanese Official Action in which they were cited is attached hereto, with what is believed to be the pertinent portion enclosed in a wavy line. An English translation of the enclosed portion is also attached hereto.

Respectfully submitted,

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RJP/lrs

INFORMATION DISCLOSURE IN AN APPLICATION		IRE STATION,	Attorney Docket No.: 8013-1156-1		Application No.: 10/607,064	
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		U.S. PATEN	T DOCUMENTS			
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		FOREIGN PAT	ENT DOCUMENTS			
Examiner Initial	Document Number Date		Country	Class	Subclass	
	JP 61-208843	09/17/1986	Japan		-	Yes No
	JP 03-153031	07/01/1991	Japan			
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	OTHER DOCUME	NTS (Including Au	thor, Title, Date, Pertiner	it Pages, E	tc.)	
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not in conformance and not considered. Include copy of this form with next communication to the applicant. * Abstract provided for the Examiner's convenience